Notice of References Cited Application/Control No. 10/758,317 Examiner DuyVu n. Deo Applicant(s)/Patent Under Reexamination CHANG ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2003/0232491	12-2003	Yamaguchi, Akihisa	438/591
	В	US-6,387,761	05-2002	Shih et al.	438/287
	С	US-2002/0197880	12-2002	Niimi et al.	438/763
	D	US-6,559,007	05-2003	Weimer, Ronald A.	438/257
	E	US-6,649,538	11-2003	Cheng et al.	438/775
	F	US-6,821,868	11-2004	Cheng et al.	438/517
	G	US-6,245,616	06-2001	Buchanan et al.	438/287
	Н	US-			
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	W	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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